

DMN3022LFG

# 30V SYNCHRONOUS N-CHANNEL ENHANCEMENT MODE MOSFET PowerDI3333-8 (Type D)

#### **Product Summary**

Device	BV <sub>DSS</sub>	R <sub>DS(ON)</sub> max
Q1	30V	22mΩ @ $V_{GS} = 5V$ , $I_D = 10A$
Q2	30V	$8m\Omega$ @ $V_{GS} = 5V$ , $I_D = 10A$

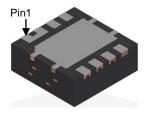
# **Description and Applications**

This new generation MOSFET is designed to minimize the on-state resistance (R<sub>DS(ON)</sub>) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- DC-DC Converters
- Power Management Functions
- Analog Switch

#### PowerDI3333-8 (Type D)





Top View

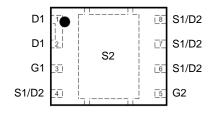
Bottom View

#### **Features and Benefits**

- 100% Unclamped Inductive Switch (UIS) Test in Production
- Low On-Resistance
- Low Input Capacitance
- · Fast Switching Speed
- Lead-Free Finish; RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)

#### **Mechanical Data**

- Case: PowerDI<sup>®</sup>3333-8 (Type D)
- Case Material: Molded Plastic, "Green" Molding Compound.
   UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Terminals: Finish Matte Tin Annealed over Copper Leadframe.
   Solderable per MIL-STD-202, Method 208 (3)
- Weight: 0.044 grams (Approximate)



Top View Pin Configuration

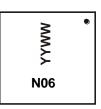
#### **Ordering Information** (Note 4)

Part Number	Case	Packaging
DMN3022LFG-7	PowerDI3333-8 (Type D)	1000 / Tape & Reel
DMN3022LFG-13	PowerDI3333-8 (Type D)	3000 / Tape & Reel

Notes:

- 1. EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant. All applicable RoHS exemptions applied.
- 2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at https://www.diodes.com/design/support/packaging/diodes-packaging/

# **Marking Information**



N06 = Product Type Marking Code YYWW = Date Code Marking YY = Last Two Digits of Year (ex: 18 = 2018) WW = Week Code (01 to 53)



# **Maximum Ratings** ( $@T_A = +25^{\circ}C$ , unless otherwise specified.)

Characteristic	Symbol	Q1	Q2	Unit	
Drain-Source Voltage	$V_{DSS}$	30		V	
Gate-Source Voltage	$V_{GSS}$	±10		V	
T <sub>C</sub>		I <sub>D</sub>	15 12		А
Continuous Drain Current @ V <sub>GS</sub> = 5V	$T_A = +25$ °C $T_A = +70$ °C	ΙD	7.6 6.1		Α
Pulsed Drain Current (10µs Pulse, Duty Cycle = 1%)	I <sub>DM</sub>	50	100	Α	
Avalanche Current (Note 6) L = 0.1mH	I <sub>AS</sub>	24	43	Α	
Avalanche Energy (Note 6) L = 0.1mH		E <sub>AS</sub>	28	92	mJ

#### Thermal Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit		
Total Power Dissipation	$T_A = +25^{\circ}C$	7	1.96	W	
Total Power Dissipation	$T_A = +70^{\circ}C$	P <sub>D</sub>	1.25		
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	0	64		
Thermal Resistance, Junction to Ambient (Note 5)	t < 10s	$R_{\theta JA}$	36	°C/W	
Thermal Resistance, Junction to Case (Note 5)	$R_{\theta JC}$	8.7			
Operating and Storage Temperature Range		$T_{J}, T_{STG}$	-55 to +150	ů	

### Electrical Characteristics Q1 (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	1	μΑ	$V_{DS} = 20V, V_{GS} = 0V$	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS} = \pm 10V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	$V_{GS(TH)}$	1	1.4	2.1	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	_	16	22	mΩ	$V_{GS} = 5V, I_D = 10A$	
Forward Transfer Admittance	Y <sub>fs</sub>	_	17	_	S	$V_{DS} = 5V, I_{D} = 8A$	
Diode Forward Voltage	$V_{SD}$	_	0.84	1	V	$V_{GS} = 0V, I_{S} = 8A$	
DYNAMIC CHARACTERISTICS (Note 8)							
Input Capacitance	C <sub>iss</sub>	_	370	481		V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V, f = 1.0MHz	
Output Capacitance	Coss	_	176	228	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>	_	8.2	10.6			
Gate Resistance	Rg	_	2.5	6.5	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$	
Total Gate Charge (V <sub>GS</sub> = 4.5V)	Qg	_	2.8	3.7			
Total Gate Charge at V <sub>TH</sub>	Q <sub>g(TH)</sub>	_	0.35	_	nC	V <sub>DS</sub> = 15V, I <sub>D</sub> = 8A	
Gate-Source Charge	$Q_{gs}$	_	0.6	_	IIC		
Gate-Drain Charge	$Q_{gd}$	_	0.5	_			
Turn-On Delay Time	t <sub>D(ON)</sub>	_	4.5	6.7		$V_{DD} = 15V, V_{GS} = 4.5V,$ $I_{D} = 8A, R_{G} = 2\Omega$	
Turn-On Rise Time	t <sub>R</sub>	_	1.8	_	ns		
Turn-Off Delay Time	t <sub>D(OFF)</sub>	_	7.2	10.8			
Turn-Off Fall Time	t <sub>F</sub>	_	1.9	_			
Reverse Recovery Time	t <sub>RR</sub>	_	11.5	_	ns		
Reverse Recovery Charge	Q <sub>RR</sub>		6.9		nC	$I_F = 8A$ , di/dt = 300A/ $\mu$ s	

Notes: 5. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

<sup>6.</sup>  $I_{AS}$  and  $E_{AS}$  ratings are based on low frequency and duty cycles to keep  $T_J = +25^{\circ}C$ . 7. Short duration pulse test used to minimize self-heating effect.

<sup>8.</sup> Guaranteed by design. Not subject to product testing.

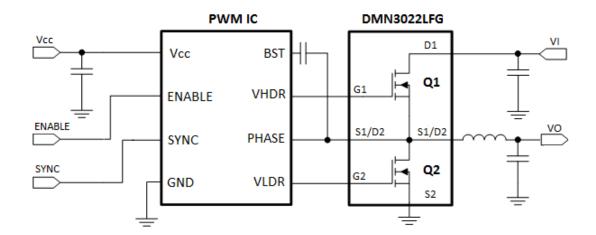


# Electrical Characteristics Q2 (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	_	_	V	$V_{GS} = 0V$ , $I_D = 250\mu A$	
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	1	_	1.0	μA	$V_{DS} = 20V, V_{GS} = 0V$	
Gate-Source Leakage	I <sub>GSS</sub>	1	_	±100	nA	$V_{GS} = \pm 10V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	8.0	0.96	1.2	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	_	6.4	8	mΩ	$V_{GS} = 5V, I_D = 10A$	
Forward Transfer Admittance	Y <sub>fs</sub>	_	33	_	S	$V_{DS} = 5V, I_{D} = 8A$	
Diode Forward Voltage	$V_{SD}$	_	0.78	1	V	$V_{GS} = 0V, I_{S} = 8A$	
DYNAMIC CHARACTERISTICS (Note 8)							
Input Capacitance	C <sub>iss</sub>	_	766	996	pF		
Output Capacitance	Coss	-	441	573	pF	$V_{DS} = 15V, V_{GS} = 0V,$ f = 1.0MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>	_	19	25	pF		
Gate Resistance	$R_{g}$	1	0.69	1.5	Ω	$V_{DS} = 0V$ , $V_{GS} = 0V$ , $f = 1MHz$	
Total Gate Charge (V <sub>GS</sub> = 4.5V)	Qg	l	6.1	8	nC		
Total Gate Charge at V <sub>TH</sub>	Q <sub>g(TH)</sub>	-	0.47	_	nC	\/ 45\/ L 0A	
Gate-Source Charge	$Q_{gs}$	_	0.8	_	nC	$V_{DS} = 15V, I_{D} = 8A$	
Gate-Drain Charge	$Q_{gd}$	_	1.1	_	nC		
Turn-On Delay Time	t <sub>D(ON)</sub>	_	5.6	8.4	ns	$V_{DD} = 15V, V_{GS} = 4.5V,$ $I_{D} = 8A, R_{G} = 2\Omega$	
Turn-On Rise Time	t <sub>R</sub>	1	2.5	_	ns		
Turn-Off Delay Time	t <sub>D(OFF)</sub>	_	11.7	17.5	ns		
Turn-Off Fall Time	t <sub>F</sub>	_	2.4		ns		
Reverse Recovery Time	t <sub>RR</sub>	_	27.9	_	ns	- I <sub>F</sub> = 8A, di/dt = 300A/μs	
Reverse Recovery Charge	$Q_{RR}$	_	9.9	_	nC		

7. Short duration pulse test used to minimize self-heating effect. 8. Guaranteed by design. Not subject to product testing. Notes:

# **Typical Circuit**





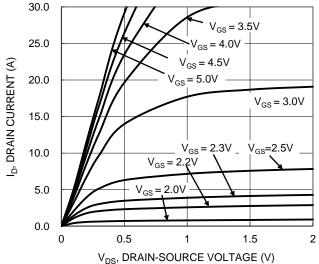


Figure 1. Q1 Typical Output Characteristic

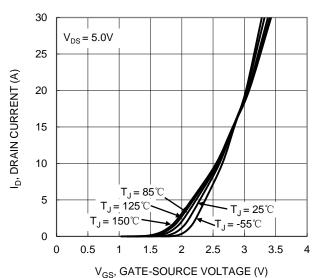


Figure 3. Q1 Typical Transfer Characteristic

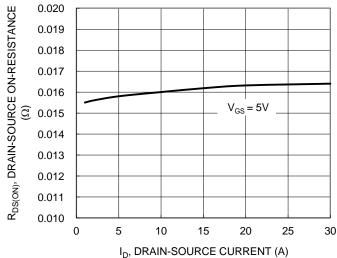
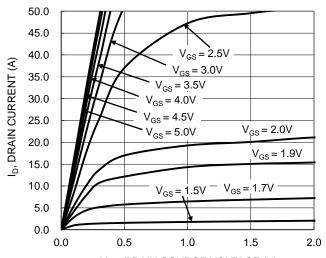


Figure 5. Q1 Typical On-Resistance vs. Drain Current and Gate Voltage



V<sub>DS</sub>, DRAIN-SOURCE VOLTAGE (V) Figure 2. Q2 Typical Output Characteristic

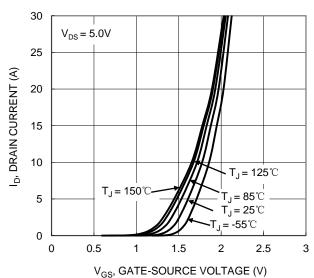


Figure 4. Q2 Typical Transfer Characteristic

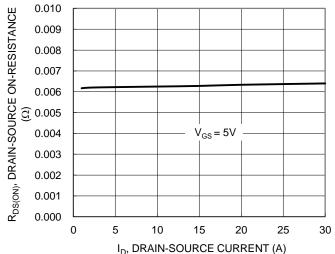
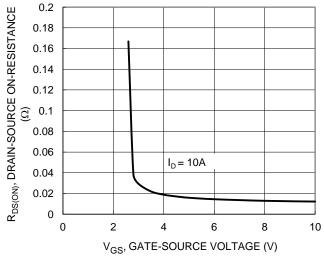


Figure 6. Q2 Typical On-Resistance vs. Drain Current and Gate Voltage







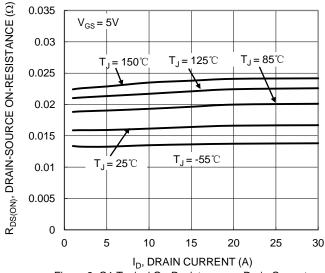


Figure 9. Q1 Typical On-Resistance vs. Drain Current and Temperature

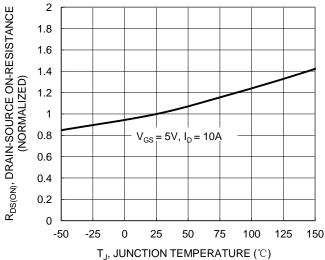


Figure 11. Q1 On-Resistance Variation with Temperature

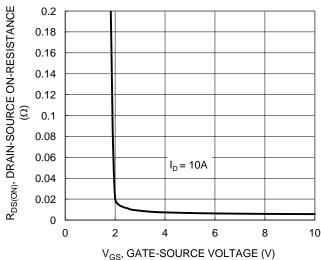


Figure 8. Q2 Typical Transfer Characteristic

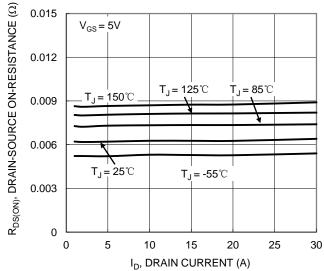


Figure 10. Q2 Typical On-Resistance vs. Drain Current and Temperature

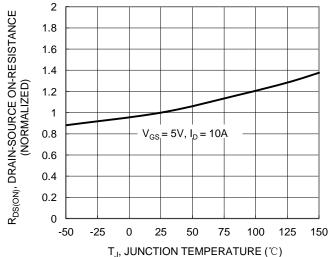


Figure 12. Q2 On-Resistance Variation with Temperature





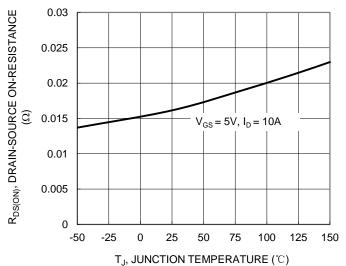
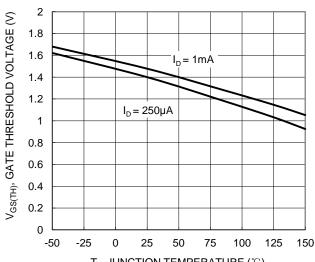


Figure 13. Q1 On-Resistance Variation with Temperature



 $\rm T_{J},\, JUNCTION\, TEMPERATURE\, (^{\circ}C)$  Figure 15. Q1 Gate Threshold Variation vs. Junction Temperature

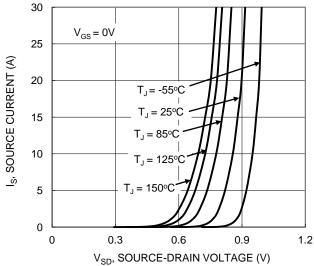


Figure 17. Q1 Diode Forward Voltage vs. Current

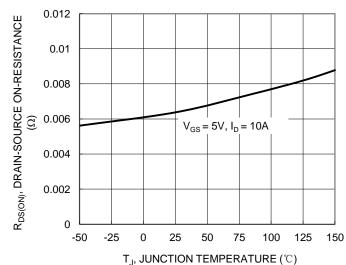


Figure 14. Q2 On-Resistance Variation with Temperature

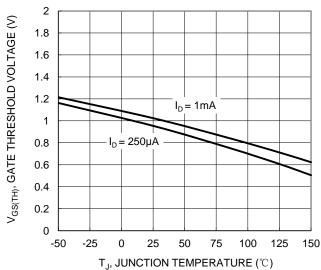
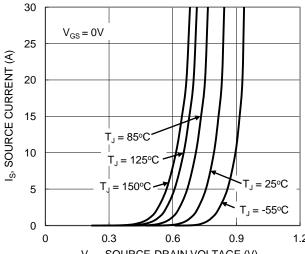


Figure 16. Q2 Gate Threshold Variation vs. Junction Temperature



V<sub>SD</sub>, SOURCE-DRAIN VOLTAGE (V) Figure 18. Q2 Diode Forward Voltage vs. Current



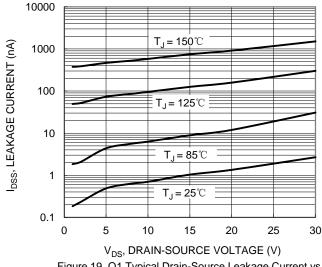


Figure 19. Q1 Typical Drain-Source Leakage Current vs. Voltage

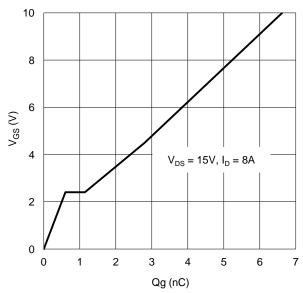


Figure 21. Q1 Gate Charge

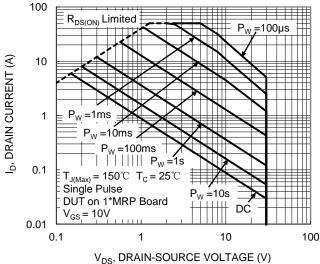


Figure 23. Q1 SOA, Safe Operation Area

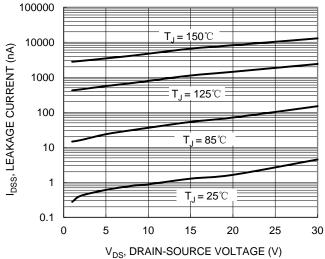


Figure 20. Q2 Typical Drain-Source Leakage Current vs.
Voltage

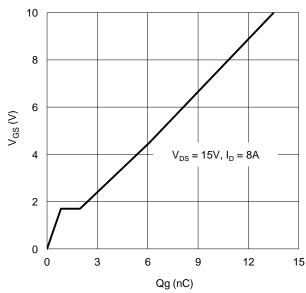


Figure 22. Q2 Gate Charge

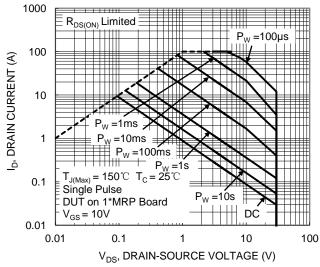


Figure 24. Q2 SOA, Safe Operation Area



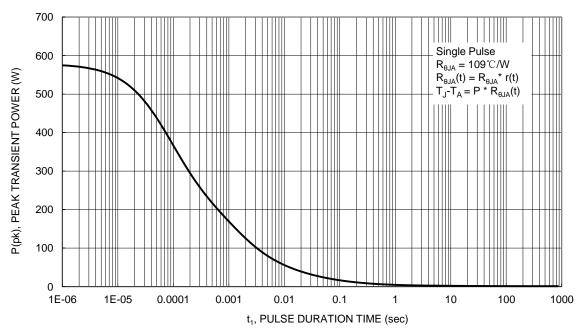


Figure 25. Single Pulse Maximum Power Dissipation

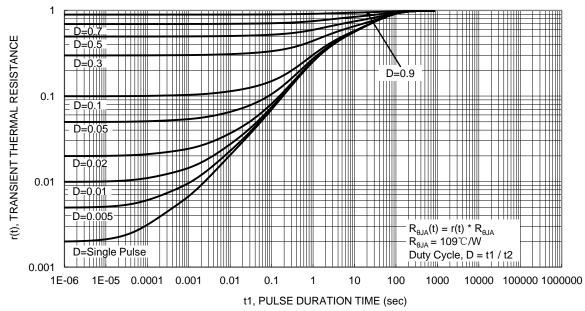


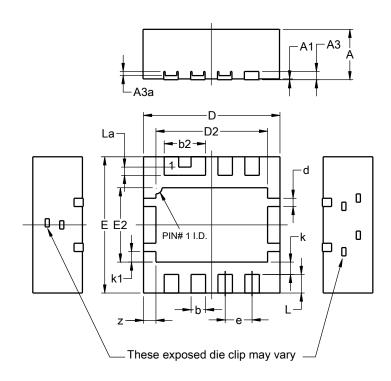
Figure 26. Transient Thermal Resistance



### **Package Outline Dimensions**

Please see http://www.diodes.com/package-outlines.html for the latest version.

#### PowerDI3333-8 (Type D)

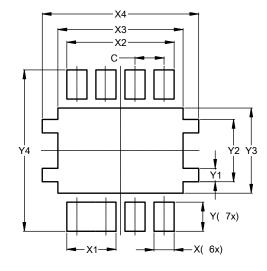


PowerDI3333-8 (Type D)						
Dim	Min	Max	Тур			
Α	1.17	1.23	1.20			
A1	0.00	0.05	0.02			
A3	0.15	0.25	0.20			
A3a	0.05	0.15	0.10			
b	0.30	0.40	0.35			
b2	0.95	1.05	1.00			
D	3.20	3.40	3.30			
D2	2.65	2.75	2.70			
Е	3.20	3.40	3.30			
E2	1.75	1.85	1.80			
d	0.15	0.25	0.20			
е			0.65			
k			0.30			
k1	0.21	0.31	0.26			
L	0.40	0.50	0.45			
La	0.15	0.25	0.20			
Z	0.25	0.35	0.30			
All Dimensions in mm						

## **Suggested Pad Layout**

Please see http://www.diodes.com/package-outlines.html for the latest version.

#### PowerDI3333-8 (Type D)



Dimensions	Value (in mm)		
С	0.650		
Х	0.450		
X1	1.100		
X2	2.400		
Х3	2.800		
X4	3.500		
Υ	0.650		
Y1	0.300		
Y2	1.390		
Y3	1.900		
Y4	3.600		



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